

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/662,160 CHUEY ET AL.	
		Examiner	Art Unit Kiet Doan	Page 1 of 1 2683

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0075133 A1	06-2002	Flick, Kenneth E.	340/5.64
	B	US-2003/0189530 A1	10-2003	Tsui, Philip Y.W.	345/48
	C	US-2002/0163440 A1	11-2002	Tsui, Philip Y.W.	340/825.69
	D	US-6,025,785 A	02-2000	Farris et al.	340/5.23
	E	US-5,554,977 A	09-1996	Jablonski et al.	340/5.26
	F	US-5,949,349 A	09-1999	Farris et al.	340/5.26
	G	US-6,154,544 A	11-2000	Farris et al.	380/262
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.